Advances in Diffraction Grating Fabrication for Space-UV Astrophysics







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High efficiency, Low scatter Gratings for UV Astronomy

- 2020 Decadal Survey large program priority: large IR/O/UV telescope (Habitable Worlds)
- Key drivers: "Worlds & Suns in Context", "Cosmic Ecosystems"
- Example: Lifetimes & dispersal of planetforming disks
- Co-spatial molecular abundances in terrestrial planet forming zones (absorption)
- How is gas lost during dispersal and how much? (emission)
- Both require high spectral resolution (R>30,000) at space-UV wavelengths to

address



High efficiency, Low scatter Gratings for UV Astronomy

- What do we need to make high-resolution UV spectroscopy happen, both near-term and for Habitable Worlds?
- -> Large format, high efficiency, low stray light reflection gratings for space-UV
- Current standard industry grating fabrication:
- \circ Mechanical ruling
- \circ lon beam etching
- Photolithography





Hoadley +2014: SEM of photo-lithographically ruled echelle grating facets for CHESS-1



High efficiency, Low scatter Gratings for UV Astronomy

- What do we need to make high-resolution UV spectroscopy happen, both near-term and for Habitable Worlds?
- -> Large format, high efficiency, low stray light reflection gratings for space-UV
- Emerging technology that shows promise to meet future UV grating needs: electron beam lithography (EBL) on silicon, with KOH etching for blazed gratings



SEM of KOH-etched Si to create blazed facet (Kruczek+ 2022)



Figure credit: D. Jaffe/INGRINS/U. Texas Austin

Electron Beam Lithography (EBL)

• EBL: rasters high energy e⁻ across resist changes solubility of resist in a developer



Process Steps

A) Deposit Process Layers



C) RIE resist to expose Si₃N₄















E) Wet-Etch Si in KOH



F) HF Soak to remove Si₃N₄



Figure credit: Cecilia Fasano, UI





Performance of EBL/KOH gratings

 Demonstrated groove efficiency from 100 – 160 nm for blazed (echelle) gratings is reaching >60%



Large format grating areas viable

INWA



MindtheGap/UVSTIG AAS 243 Splinter Session, 01/09/2023

Kruczek+ 2022

Performance of EBL/KOH gratings

 Improved stray light control in an integrated spectograph system





Kruczek+ 2022

Limitations & Challenges



AFM of imprinted grating by Mateo Batkis, GSFC

- Resist

SEM taken by Cecilia at Iowa's Central Microscopy

Research Facility

- Large write areas possible, but time consuming
- Paths forward: Nano-imprinting, grating arrays



Limitations & Challenges

• Spectral "ghosts": Errors in write field pattern placement & correction



Can see field boundaries interferometrically



SEM images of stitch error



Different stitch error across the same substrate

Spherical CRISM Grating: significant "ghosting"



Limitations & Challenges

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SEM images of stitch error



Different stitch error across the same substrate

(b) V1 - write areas run diagonal to grooves

Disp. Dir.

(a) CHESS Echelle

(c) V2 - write areas run parallel/perpendicular to grooves

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Customizable Gratings for Space UV Spectroscopy

- "Customizable" = control over groove period, pattern, blaze angle, substrate curvature, size...
- Leads to innovative instrument concepts



Direct Write Blazing via TASTE (McCoy et al. 2020, McCurdy et al. 2020)

ESCAPE grating: radiallyruled grooves with a "curve" (Grisé: 11821-28, Kruczek: 11821-12)





CRISM Spherical Grating with two blaze angles, (Wilson et al. 2003)

Summary

- UV Gratings for future UV spectrograph missions must be improved to achieve necessary gains in SNR, sensitivity
- EBL+KOH offers a promising path forward
- Promising results: High peak groove efficiencies demonstrated, low stray light backgrounds in spectrographs, large format ruling on the way
- Challenges ahead: Continuing to increase grating size, "ghosting" patterns
- Looking ahead: Improving EBL writing for customization of patterning (VLS, curved substrates, aberration correction, ...), TASTE, grating arrays, ...





SEM of KOH-etch blaze profile (~54 degree blaze angle)

F16 7 0kV x80 0k



Top shows 3-nm layer of Iridium coating for SEM imaging, while the bottom shows 30-nm Au layer for UV testing.